Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
		((test$ near memory) (BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:12
L1	1987	yamada.in. and "integrated circuit"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/12/26 20:17
L2	2245	yamada.in. and "integrated circuit"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
L3	6	yamada.in. and "integrated circuit" and advantest.as.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
L4	0	(osamu and yamada).in. and "integrated circuit" and advantest. as.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
L5	38	(osamu and yamada).in. and "integrated circuit"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
L6	0	(osamu and yamada).in. and "integrated circuit" and (memory near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:19
L7	129	714/738.CCLS. and "integrated circuit" and (memory near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:19
S1	11768	test$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:02

S2	55309	test$3 with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:02
S3	36	(test$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:18
S4	8	(test$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver$5 near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 16:59
S5	0	((BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/738.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S6	1	((BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/733.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S7	2	(BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH) near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10

S8	36	(BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S9	52	((test$3 near memory) (BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:12
S10	10	("4754215", "4862460", "5214654", "5314492", "5739778").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/04/21 18:01
S11	2	"6065145".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/17 16:52
S12	1256	clock near align$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/17 16:52
S13	1370	clock near align$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/17 16:52
S14	9	(clock near align$5) and (delay near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/17 16:53